

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/605,560	LIU ET AL.	
Examiner	Art Unit	
Isaac T. Tecklu	2192	

SEARCHED				
Class	Subclass	Date	Examiner	
717	171	5/25/2007	IT	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
Searched EAST all database	5/25/2007	!T			
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